DATA SHEET

74LVC2244A

Octal buffer/line driver; with 30 Ω serie termination resistors; 5 V tolerant input/output; 3-state

Product specification
2002 Dec 13
Supersedes data of 2002 Jun 18

Philips Semiconductors

PHILIPS

Octal buffer/line driver; with 30 Ω serie termination resistors; 5 V tolerant input/output; 3-state

74LVC2244A

FEATURES

- 5 V tolerant inputs/outputs for interfacing with 5 V logic
- Wide supply voltage range from 1.2 to 3.6 V
- CMOS low power consumption
- Direct interface with TTL levels
- Inputs accept voltages up to 5.5 V
- Integrated 30 Ω termination resistors
- Complies with JEDEC standard no. 8-1A
- ESD protection:
  HBM EIA/JESD22-A114-A exceeds 2000 V
  MM EIA/JESD22-A115-A exceeds 200 V.
- Specified from –40 to +85 °C and –40 to +125 °C.

DESCRIPTION

The 74LVC2244A is a high-performance, low-power, low-voltage, Si-gate CMOS device, superior to most advanced CMOS compatible TTL families.

Inputs can be driven from either 3.3 or 5 V devices. In 3-state operation outputs can handle 5 V. These features allow the use of these devices as translators in a mixed 3.3 and 5 V environment.

The 74LVC2244A is an octal non-inverting buffer/line driver with 3-state outputs. The 3-state outputs are controlled by the output enable inputs $1\overline{OE}$ and $2\overline{OE}$. A HIGH on $n\overline{OE}$ causes the outputs to assume a high-impedance OFF-state. Schmitt-trigger action at all inputs makes the circuit highly tolerant for slower input rise and fall times. The 74LVC2244A is designed with 30 Ω series termination resistors in both HIGH and LOW output stages to reduce line noise.

QUICK REFERENCE DATA

GND = 0 V; T_{amb} = 25 °C; $t_r = t_f \leq 2.5$ ns.

SYMBOL	PARAMETER	CONDITIONS	TYPICAL	UNIT
t_{PHL}/t_{PLH}	propagation delay nA_n to nY_n	C_L = 50 pF; V_{CC} = 3.3 V	3.1	ns
C_I	input capacitance		4.0	pF
C_{PD}	power dissipation capacitance per buffer	V_{CC} = 3.3 V; notes 1 and 2	8	pF

Notes

1. C_{PD} is used to determine the dynamic power dissipation (P_D in μW).
   $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma(C_L \times V_{CC}^2 \times f_o)$ where:
   f_i = input frequency in MHz;
   f_o = output frequency in MHz;
   C_L = output load capacitance in pF;
   V_{CC} = supply voltage in Volts;
   N = total switching outputs;
   $\Sigma(C_L \times V_{CC}^2 \times f_o)$ = sum of the outputs.
2. The condition is V_I = GND to V_{CC}.

ORDERING INFORMATION

TYPE NUMBER	PACKAGE				
	TEMPERATURE RANGE	PINS	PACKAGE	MATERIAL	CODE
74LVC2244AD	–40 to +125 °C	20	SO20	plastic	SOT163-1
74LVC2244ADB	–40 to +125 °C	20	SSOP20	plastic	SOT339-1
74LVC2244APW	–40 to +125 °C	20	TSSOP20	plastic	SOT360-1
74LVC2244ABQ	–40 to +125 °C	20	DHVQFN20	plastic	SOT764-1

FUNCTION TABLE

See note 1.

INPUT		OUTPUT
$n\overline{OE}$	nA_n	nY_n
L	L	L
L	H	H
H	X	Z

Note

1. H = HIGH voltage level;
   L = LOW voltage level;
   X = don't care;
   Z = high-impedance OFF-state.

PINNING

PIN	SYMBOL	DESCRIPTION
1	$1\overline{OE}$	output enable input (active LOW)
2	$1A_0$	data input
3	$2Y_0$	bus output
4	$1A_1$	data input
5	$2Y_1$	bus output
6	$1A_2$	data input
7	$2Y_2$	bus output
8	$1A_3$	data input
9	$2Y_3$	bus output
10	GND	ground (0 V)
11	$2A_3$	data input
12	$1Y_3$	data output
13	$2A_2$	data input
14	$1Y_2$	data output
15	$2A_1$	data input
16	$1Y_1$	data output
17	$2A_0$	data input
18	$1Y_0$	data output
19	$2\overline{OE}$	output enable input (active LOW)
20	V_{CC}	supply voltage

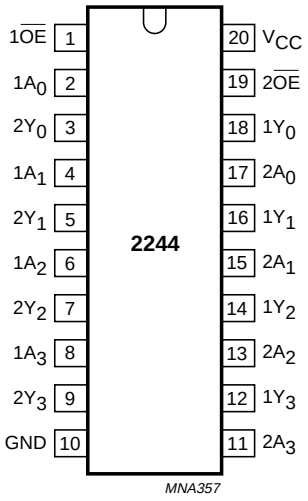
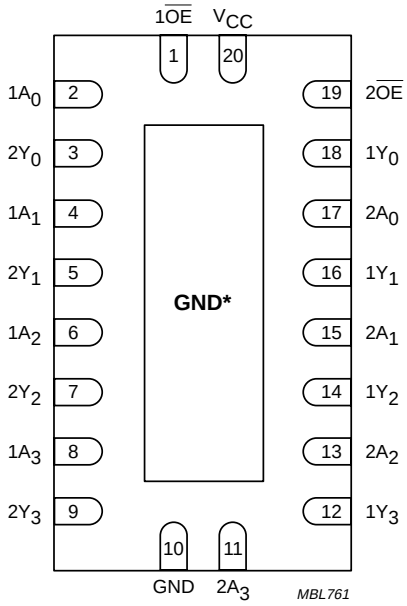


Fig.1 Pin configuration SO20 and (T)SSOP20.



* The die substrate is attached to this pad using conductive die attach material. It can not be used as a supply pin or input.

Fig.2 Pin configuration DHVQFN20.

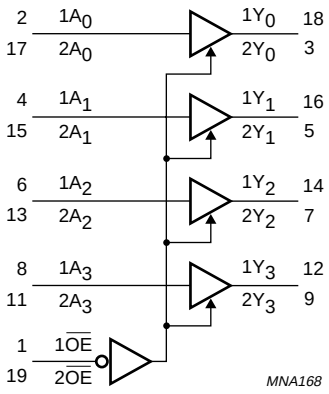


Fig.3 Logic symbol.

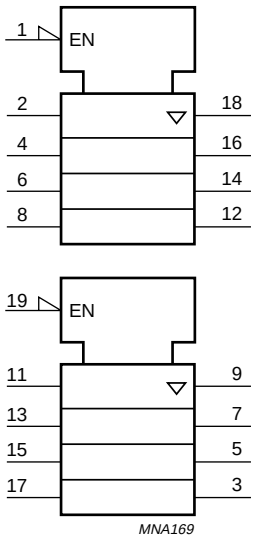


Fig.4 Logic symbol (IEEE/IEC).

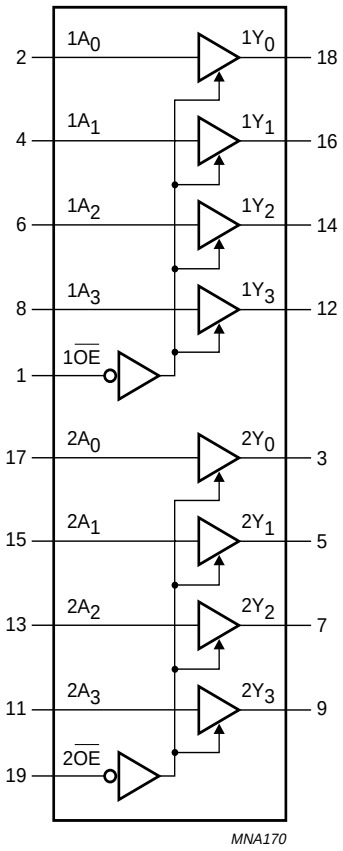


Fig.5 Logic diagram.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{CC}	supply voltage	for maximum speed performance	2.7	3.6	V
		for low-voltage applications	1.2	3.6	V
V_I	input voltage		0	5.5	V
V_O	output voltage	output HIGH or LOW state	0	V_{CC}	V
		output 3-state	0	5.5	V
T_{amb}	operating ambient temperature		–40	+125	°C
t_r, t_f	input rise and fall times	V_{CC} = 1.2 to 2.7 V	0	20	ns/V
		V_{CC} = 2.7 to 3.6 V	0	10	ns/V

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134); voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{CC}	supply voltage		–0.5	+6.5	V
I_{IK}	input diode current	$V_I < 0$	–	–50	mA
V_I	input voltage	note 1	–0.5	+6.5	V
I_{OK}	output diode current	$V_O > V_{CC}$ or $V_O < 0$	–	±50	mA
V_O	output voltage	output HIGH or LOW state; note 1	–0.5	V_{CC} + 0.5	V
		output 3-state; note 1	–0.5	+6.5	V
I_O	output source or sink current	V_O = 0 to V_{CC}	–	±50	mA
I_{CC}, I_{GND}	V_{CC} or GND current		–	±100	mA
T_{stg}	storage temperature		–65	+150	°C
P_{tot}	power dissipation	T_{amb} = –40 to +125 °C; note 2	–	500	mW

Notes

1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. For SO20 packages: above 70 °C derate linearly with 8 mW/K.
   For SSOP20 and TSSOP20 packages: above 60 °C derate linearly with 5.5 mW/K.
   For DHVQFN20 packages: above 60 °C derate linearly with 5.5 mW/K.

DC CHARACTERISTICS

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	TEST CONDITIONS		MIN.	TYP.(1)	MAX.	UNIT
		OTHER	V_{CC} (V)				
T_{amb} = −40 to +85 °C							
V_{IH}	HIGH-level input voltage		1.2	V_{CC}	–	–	V
			2.7 to 3.6	2.0	–	–	V
V_{IL}	LOW-level input voltage		1.2	–	–	0	V
			2.7 to 3.6	–	–	0.8	V
V_{OH}	HIGH-level output voltage	V_I = V_{IH} or V_{IL}					
		I_O = −100 μA	2.7 to 3.6	V_{CC} − 0.2	V_{CC}	–	V
		I_O = −6 mA	2.7	V_{CC} − 0.5	–	–	V
		I_O = −12 mA	3.0	V_{CC} − 0.8	–	–	V
V_{OL}	LOW-level output voltage	V_I = V_{IH} or V_{IL}					
		I_O = 100 μA	2.7 to 3.6	–	0	0.2	V
		I_O = 6 mA	2.7	–	–	0.4	V
		I_O = 12 mA	3.0	–	–	0.55	V
I_{LI}	input leakage current	V_I = 5.5 V or GND	3.6	–	±0.1	±5	μA
I_{OZ}	3-state output OFF-state current	V_I = V_{IH} or V_{IL}; V_O = 5.5 V or GND	3.6	–	0.1	±10	μA
I_{off}	power off leakage supply	V_I or V_O = 5.5 V	0.0	–	0.1	±10	μA
I_{CC}	quiescent supply current	V_I = V_{CC} or GND; I_O = 0	3.6	–	0.1	20	μA
ΔI_{CC}	additional quiescent supply current per pin	V_I = V_{CC} − 0.6 V; I_O = 0	2.7 to 3.6	–	5	500	μA

SYMBOL	PARAMETER	TEST CONDITIONS		MIN.	TYP.(1)	MAX.	UNIT
		OTHER	V_{CC} (V)				
T_{amb} = −40 to +125 °C							
V_{IH}	HIGH-level input voltage		1.2	V_{CC}	–	–	V
			2.7 to 3.6	2.0	–	–	V
V_{IL}	LOW-level input voltage		1.2	–	–	0	V
			2.7 to 3.6	–	–	0.8	V
V_{OH}	HIGH-level output voltage	V_I = V_{IH} or V_{IL}			–		
		I_O = −100 μA	2.7 to 3.6	V_{CC} − 0.3	–	–	V
		I_O = −6 mA	2.7	V_{CC} − 0.65	–	–	V
		I_O = −12 mA	3.0	V_{CC} − 1	–	–	V
V_{OL}	LOW-level output voltage	V_I = V_{IH} or V_{IL}			–		
		I_O = 100 μA	2.7 to 3.6	–	–	0.3	V
		I_O = 6 mA	2.7	–	–	0.6	V
		I_O = 12 mA	3.0	–	–	0.8	V
I_{LI}	input leakage current	V_I = 5.5 V or GND	3.6	–	–	±20	μA
I_{OZ}	3-state output OFF-state current	V_I = V_{IH} or V_{IL}; V_O = 5.5 V or GND	3.6	–	–	±20	μA
I_{off}	power off leakage supply	V_I or V_O = 5.5 V	0.0	–	–	±20	μA
I_{CC}	quiescent supply current	V_I = V_{CC} or GND; I_O = 0	3.6	–	–	40	μA
ΔI_{CC}	additional quiescent supply current per pin	V_I = V_{CC} − 0.6 V; I_O = 0	2.7 to 3.6	–	–	5000	μA

Note

1. All typical values are measured at V_{CC} = 3.3 V and T_{amb} = 25 °C.

AC CHARACTERISTICS

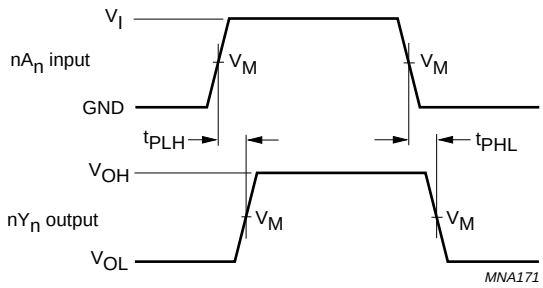
GND = 0 V; $t_r = t_f \leq 2.5$ ns.

SYMBOL	PARAMETER	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
		WAVEFORMS	V_{CC} (V)				
T_{amb} = −40 to +85 °C							
t_{PHL}/t_{PLH}	propagation delay nA_n to nY_n	see Figs 6 and 8	1.2	–	35	–	ns
			2.7	1.5	3.8	6.4	ns
			3.0 to 3.6	1.5	3.1(1)	5.5	ns
t_{PZH}/t_{PZL}	3-state output enable time $n\overline{OE}$ to nY_n	see Figs 7 and 8	1.2	–	38	–	ns
			2.7	1.5	5.0	8.1	ns
			3.0 to 3.6	1.0	3.9(1)	7.1	ns
t_{PHZ}/t_{PLZ}	3-state output disable time $n\overline{OE}$ to nY_n	see Figs 7 and 8	1.2	–	9.0	–	ns
			2.7	1.5	5.0	6.4	ns
			3.0 to 3.6	1.5	2.8(1)	5.4	ns
$t_{sk(0)}$	skew	note 2		–	–	1.0	ns
T_{amb} = −40 to +125 °C							
t_{PHL}/t_{PLH}	propagation delay nA_n to nY_n	see Figs 6 and 8	1.2	–	–	–	ns
			2.7	1.5	–	8.0	ns
			3.0 to 3.6	1.5	–	7.0	ns
t_{PZH}/t_{PZL}	3-state output enable time $n\overline{OE}$ to nY_n	see Figs 7 and 8	1.2	–	–	–	ns
			2.7	1.5	–	10.5	ns
			3.0 to 3.6	1.0	–	9.0	ns
t_{PHZ}/t_{PLZ}	3-state output disable time $n\overline{OE}$ to nY_n	see Figs 7 and 8	1.2	–	–	–	ns
			2.7	1.5	–	8.0	ns
			3.0 to 3.6	1.5	–	7.0	ns
$t_{sk(0)}$	skew	note 2		–	–	1.5	ns

Notes

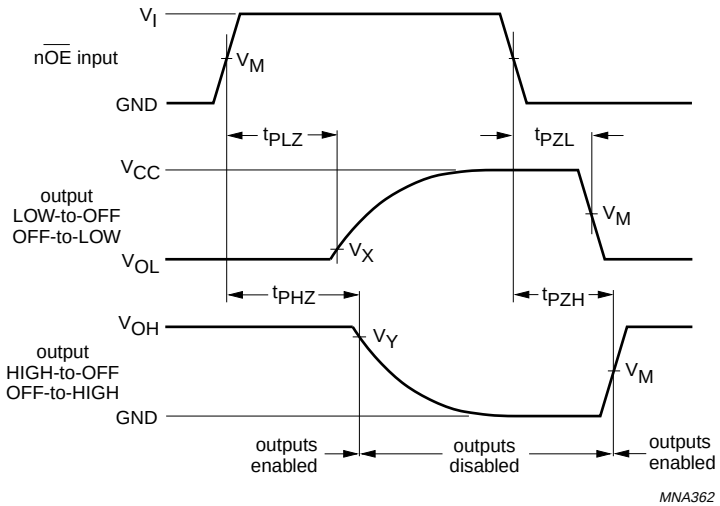
1. Typical values are measured at V_{CC} = 3.3 V.
2. Skew between any two outputs of the same package switching in the same direction. This parameter is guaranteed by design.

AC WAVEFORMS



V_M = 1.5 V at $V_{CC} \geq$ 2.7 V;
$V_M = 0.5V_{CC}$ at V_{CC} < 2.7 V;
V_{OL} and V_{OH} are typical output voltage drop that occur with the output load.

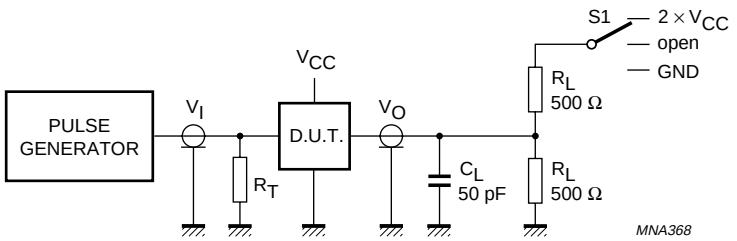
Fig.6 The input nA to output nY propagation delays.



V_M = 1.5 V at $V_{CC} \geq$ 2.7 V;
$V_M = 0.5V_{CC}$ at V_{CC} < 2.7 V;
$V_X = V_{OL}$ + 0.3 V at $V_{CC} \geq$ 2.7 V;
$V_X = V_{OL}$ + 0.1 V at V_{CC} < 2.7 V;
$V_Y = V_{OH}$ – 0.3 V at $V_{CC} \geq$ 2.7 V;
$V_Y = V_{OH}$ – 0.1 V at V_{CC} < 2.7 V.

V_{OL} and V_{OH} are typical output voltage drop that occur with the output load.

Fig.7 3-state enable and disable times.



SWITCH POSITION	
TEST	**S1**
t_{PLH}/t_{PHL}	open
t_{PLZ}/t_{PZL}	$2 \times V_{CC}$
t_{PHZ}/t_{PZH}	GND

V_{CC}	V_I
< 2.7 V	V_{CC}
2.7 to 3.6 V	2.7 V

Definitions for test circuits:

R_L = Load resistor.

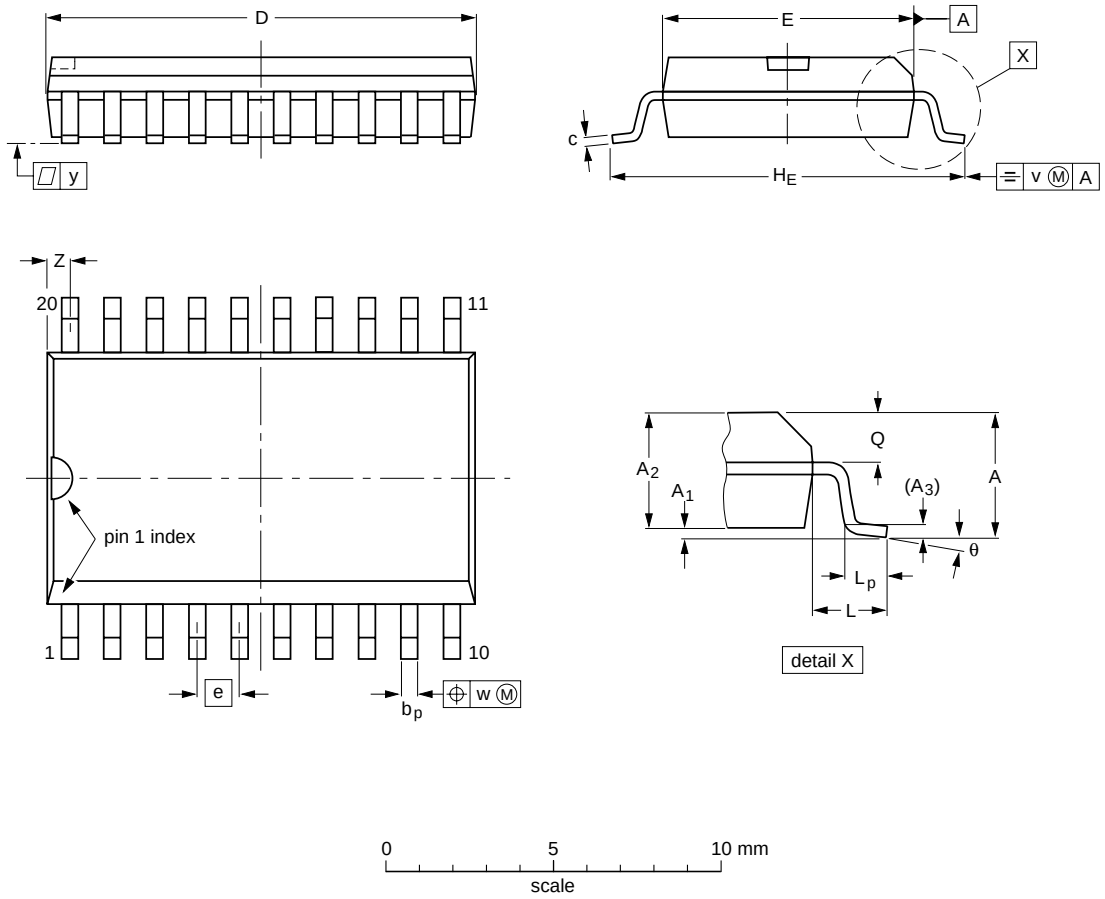
C_L = Load capacitance including jig and probe capacitance.

R_T = Termination resistance should be equal to the output impedance Z_o of the pulse generator.

Fig.8 Load circuitry for switching times.

PACKAGE OUTLINES

SO20: plastic small outline package; 20 leads; body width 7.5 mm **SOT163-1**



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

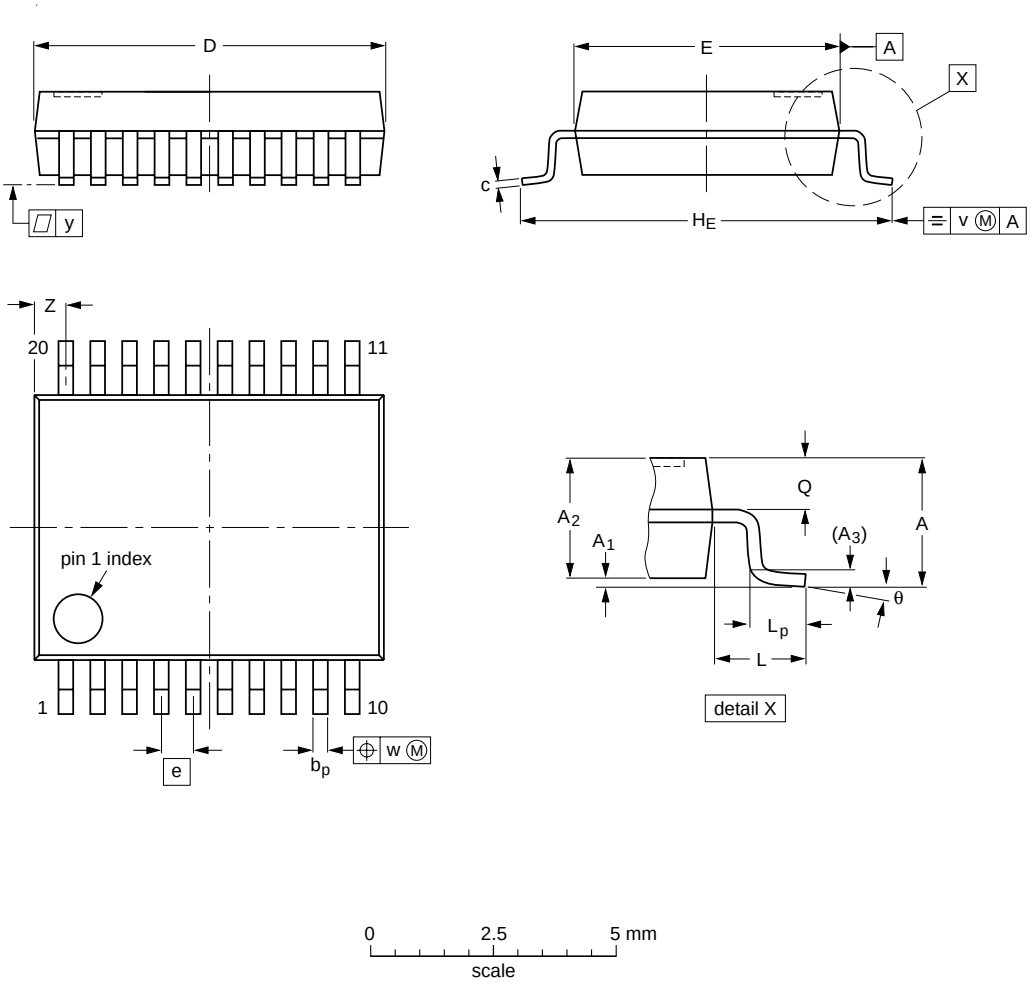
UNIT	A max.	A_1	A_2	A_3	b_p	c	D (1)	E (1)	e	H_E	L	L_p	Q	v	w	y	Z (1)	θ
mm	2.65	0.30 0.10	2.45 2.25	0.25	0.49 0.36	0.32 0.23	13.0 12.6	7.6 7.4	1.27	10.65 10.00	1.4	1.1 0.4	1.1 1.0	0.25	0.25	0.1	0.9 0.4	8^o 0^o
inches	0.10	0.012 0.004	0.096 0.089	0.01	0.019 0.014	0.013 0.009	0.51 0.49	0.30 0.29	0.050	0.419 0.394	0.055	0.043 0.016	0.043 0.039	0.01	0.01	0.004	0.035 0.016	

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT163-1	075E04	MS-013				~~97-05-22~~ 99-12-27

SSOP20: plastic shrink small outline package; 20 leads; body width 5.3 mm **SOT339-1**



DIMENSIONS (mm are the original dimensions)

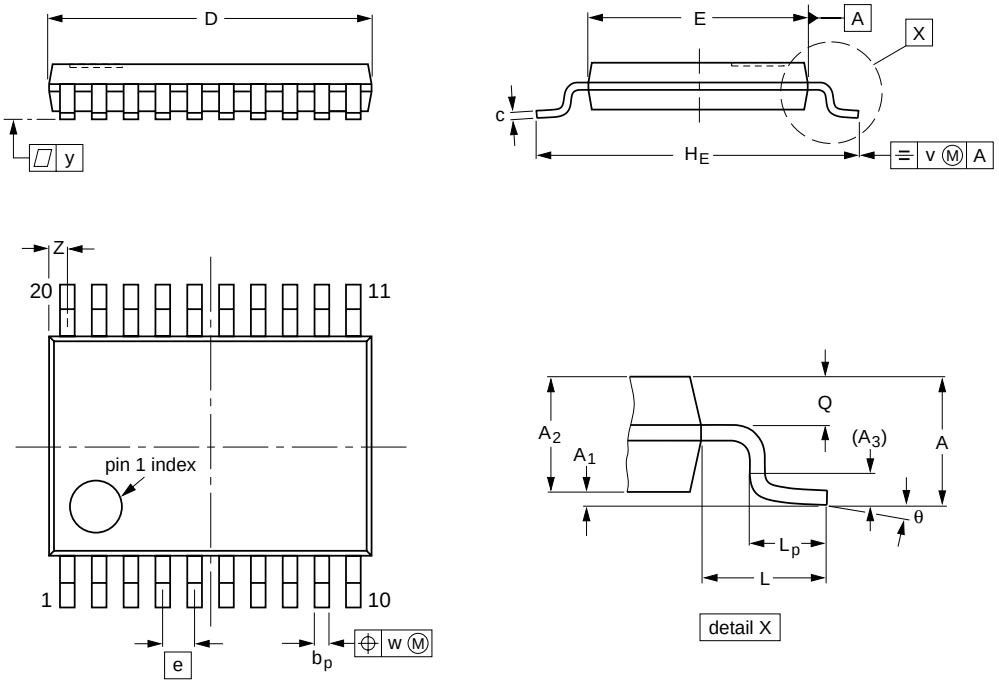
UNIT	A max.	A_1	A_2	A_3	b_p	c	$D^{(1)}$	$E^{(1)}$	e	H_E	L	L_p	Q	v	w	y	$Z^{(1)}$	θ
mm	2.0	0.21 0.05	1.80 1.65	0.25	0.38 0.25	0.20 0.09	7.4 7.0	5.4 5.2	0.65	7.9 7.6	1.25	1.03 0.63	0.9 0.7	0.2	0.13	0.1	0.9 0.5	8^o 0^o

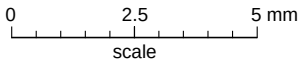
Note

1. Plastic or metal protrusions of 0.20 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT339-1		MO-150				~~95-02-04~~ 99-12-27

TSSOP20: plastic thin shrink small outline package; 20 leads; body width 4.4 mm **SOT360-1**





DIMENSIONS (mm are the original dimensions)

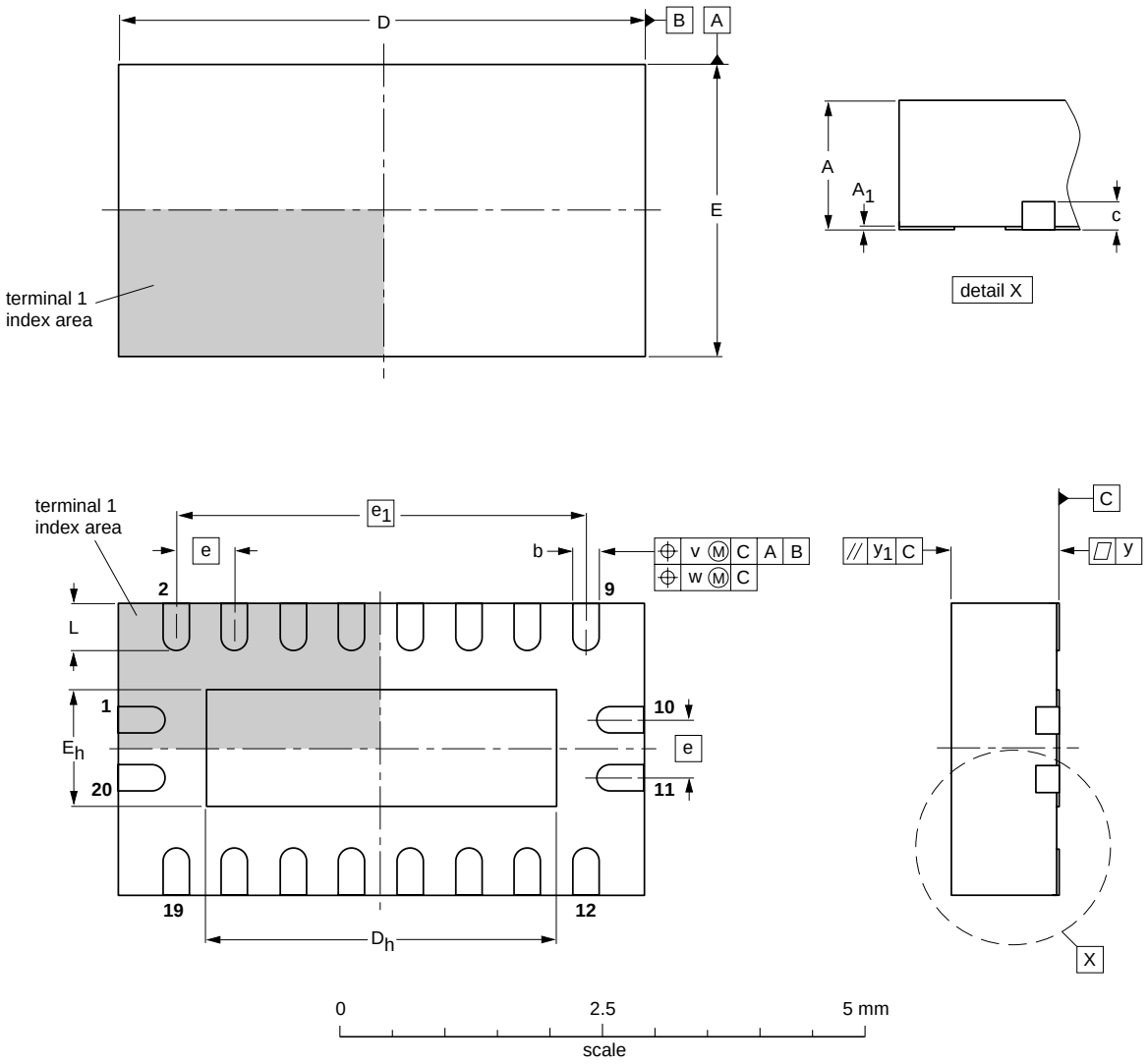
UNIT	A max.	A_1	A_2	A_3	b_p	c	D (1)	E (2)	e	H_E	L	L_p	Q	v	w	y	Z (1)	θ
mm	1.10	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	6.6 6.4	4.5 4.3	0.65	6.6 6.2	1.0	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.5 0.2	8^o 0^o

Notes

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT360-1		MO-153				~~95-02-04~~ 99-12-27

DHVQFN20: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 20 terminals; body 2.5 x 4.5 x 0.85 mm **SOT764-1**



DIMENSIONS (mm are the original dimensions)

UNIT	A(1) max.	A_1	b	c	D(1)	D_h	E(1)	E_h	e	e_1	L	v	w	y	y_1
mm	1	0.05 0.00	0.30 0.18	0.2	4.6 4.4	3.15 2.85	2.6 2.4	1.15 0.85	0.5	3.5	0.5 0.3	0.1	0.05	0.05	0.1

Note

1. Plastic or metal protrusions of 0.075 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT764-1	- - -	- - -	- - -			~~02-07-05~~ 02-10-17

SOLDERING

Introduction to soldering surface mount packages

This text gives a very brief insight to a complex technology. A more in-depth account of soldering ICs can be found in our *"Data Handbook IC26; Integrated Circuit Packages"* (document order number 9398 652 90011).

There is no soldering method that is ideal for all surface mount IC packages. Wave soldering can still be used for certain surface mount ICs, but it is not suitable for fine pitch SMDs. In these situations reflow soldering is recommended.

Reflow soldering

Reflow soldering requires solder paste (a suspension of fine solder particles, flux and binding agent) to be applied to the printed-circuit board by screen printing, stencilling or pressure-syringe dispensing before package placement.

Several methods exist for reflowing; for example, convection or convection/infrared heating in a conveyor type oven. Throughput times (preheating, soldering and cooling) vary between 100 and 200 seconds depending on heating method.

Typical reflow peak temperatures range from 215 to 250 °C. The top-surface temperature of the packages should preferable be kept below 220 °C for thick/large packages, and below 235 °C for small/thin packages.

Wave soldering

Conventional single wave soldering is not recommended for surface mount devices (SMDs) or printed-circuit boards with a high component density, as solder bridging and non-wetting can present major problems.

To overcome these problems the double-wave soldering method was specifically developed.

If wave soldering is used the following conditions must be observed for optimal results:

- Use a double-wave soldering method comprising a turbulent wave with high upward pressure followed by a smooth laminar wave.
- For packages with leads on two sides and a pitch (e):
  - larger than or equal to 1.27 mm, the footprint longitudinal axis is **preferred** to be parallel to the transport direction of the printed-circuit board;
  - smaller than 1.27 mm, the footprint longitudinal axis **must** be parallel to the transport direction of the printed-circuit board.

  The footprint must incorporate solder thieves at the downstream end.
- For packages with leads on four sides, the footprint must be placed at a 45° angle to the transport direction of the printed-circuit board. The footprint must incorporate solder thieves downstream and at the side corners.

During placement and before soldering, the package must be fixed with a droplet of adhesive. The adhesive can be applied by screen printing, pin transfer or syringe dispensing. The package can be soldered after the adhesive is cured.

Typical dwell time is 4 seconds at 250 °C.
A mildly-activated flux will eliminate the need for removal of corrosive residues in most applications.

Manual soldering

Fix the component by first soldering two diagonally-opposite end leads. Use a low voltage (24 V or less) soldering iron applied to the flat part of the lead. Contact time must be limited to 10 seconds at up to 300 °C.

When using a dedicated tool, all other leads can be soldered in one operation within 2 to 5 seconds between 270 and 320 °C.

Suitability of surface mount IC packages for wave and reflow soldering methods

PACKAGE[1]	SOLDERING METHOD	
	WAVE	REFLOW[2]
BGA, LBGA, LFBGA, SQFP, TFBGA, VFBGA	not suitable	suitable
DHVQFN, HBCC, HBGA, HLQFP, HSQFP, HSOP, HTQFP, HTSSOP, HVQFN, HVSON, SMS	not suitable[3]	suitable
PLCC[4], SO, SOJ	suitable	suitable
LQFP, QFP, TQFP	not recommended[4][5]	suitable
SSOP, TSSOP, VSO	not recommended[6]	suitable

Notes

1. For more detailed information on the BGA packages refer to the *"(LF)BGA Application Note*" (AN01026); order a copy from your Philips Semiconductors sales office.
2. All surface mount (SMD) packages are moisture sensitive. Depending upon the moisture content, the maximum temperature (with respect to time) and body size of the package, there is a risk that internal or external package cracks may occur due to vaporization of the moisture in them (the so called popcorn effect). For details, refer to the Drypack information in the *"Data Handbook IC26; Integrated Circuit Packages; Section: Packing Methods"*.
3. These packages are not suitable for wave soldering. On versions with the heatsink on the bottom side, the solder cannot penetrate between the printed-circuit board and the heatsink. On versions with the heatsink on the top side, the solder might be deposited on the heatsink surface.
4. If wave soldering is considered, then the package must be placed at a 45° angle to the solder wave direction. The package footprint must incorporate solder thieves downstream and at the side corners.
5. Wave soldering is suitable for LQFP, TQFP and QFP packages with a pitch (e) larger than 0.8 mm; it is definitely not suitable for packages with a pitch (e) equal to or smaller than 0.65 mm.
6. Wave soldering is suitable for SSOP and TSSOP packages with a pitch (e) equal to or larger than 0.65 mm; it is definitely not suitable for packages with a pitch (e) equal to or smaller than 0.5 mm.

DATA SHEET STATUS

LEVEL	DATA SHEET STATUS(1)	PRODUCT STATUS(2)(3)	DEFINITION
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
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2. The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL http://www.semiconductors.philips.com.
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